Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/695,791	TANAKA ET AL.	
Examiner	Art Unit	
Patrick J. Lee	2878	

SEARCHED						
Class	Subclass	Date	Examiner			
250	214R, 231.13, 231.14, 231.18	3123105 4(6105 4/6105 4/6105	PL			
356	614, 616		PL			
341	13		PL			
33	1PT		PL			
250	208.1	4/12/2005	PL			
250	208.2	4/12/2005	PL			

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
	<u>L</u>					

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
East (see attached)	3/23/2005	PL .
Consulted w/ S. Allen	4/5/2005	PL
East (see attached)	4/6/2005	PL
East (see attached)	4/11/2005	PL
East (see attached)	4/12/2005	PL